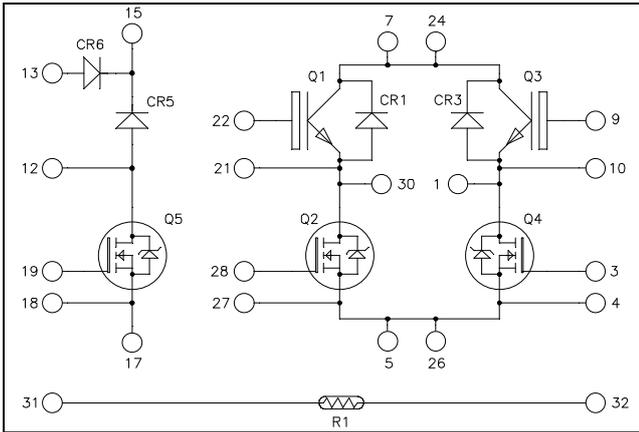


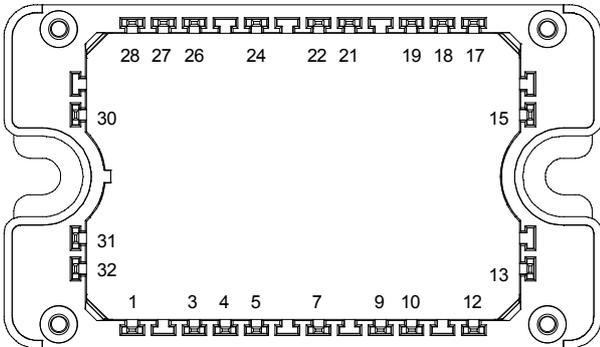
**Full – Bridge + boost chopper  
CoolMOS™ & Trench + Field Stop IGBT3  
Power module**



Top switches : Trench + Field Stop IGBT3

Bottom switches : CoolMOS™

Boost chopper : CoolMOS™



All multiple inputs and outputs must be shorted together  
7/24 ; 5/26

**Trench & Field Stop IGBT3 Q1, Q3:**  
 $V_{CES} = 600V$  ;  $I_C = 50A$  @  $T_c = 80^\circ C$

**CoolMOS™ Q2, Q4:**

$V_{DSS} = 600V$

$R_{DSon} = 45m\Omega$  max @  $T_j = 25^\circ C$

### Application

- Solar converter

### Features

- **Q2, Q4 & Q5 CoolMOS™**
  - Ultra low  $R_{DSon}$
  - Low Miller capacitance
  - Ultra low gate charge
  - Avalanche energy rated
- **Q1, Q3 Trench & Field Stop IGBT3**
  - Low voltage drop
  - Switching frequency up to 20 kHz
  - RBSOA & SCSOA rated
  - Low tail current

- Very low stray inductance
- Kelvin source for easy drive
- Internal thermistor for temperature monitoring
- High level of integration

### Benefits

- Optimized conduction & switching losses
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- Easy paralleling due to positive  $T_C$  of  $V_{CEsat}$
- RoHS Compliant

**CAUTION:** These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on [www.microsemi.com](http://www.microsemi.com)

**All ratings @  $T_j = 25^\circ C$  unless otherwise specified**

**1. Top switches**
**1.1 Top Trench + Field Stop IGBT3 characteristics (per IGBT)**
**Electrical Characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
I <sub>CES</sub>	Zero Gate Voltage Collector Current	V <sub>GE</sub> = 0V, V <sub>CE</sub> = 600V			250	μA
V <sub>CE(sat)</sub>	Collector Emitter Saturation Voltage	V <sub>GE</sub> = 15V I <sub>C</sub> = 50A		1.5 1.7	1.9	V
		T <sub>j</sub> = 25°C T <sub>j</sub> = 150°C				
V <sub>GE(th)</sub>	Gate Threshold Voltage	V <sub>GE</sub> = V <sub>CE</sub> , I <sub>C</sub> = 600μA	5.0	5.8	6.5	V
I <sub>GES</sub>	Gate – Emitter Leakage Current	V <sub>GE</sub> = 20V, V <sub>CE</sub> = 0V			600	nA

**Dynamic Characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
C <sub>ies</sub>	Input Capacitance	V <sub>GE</sub> = 0V		3150		pF
C <sub>oes</sub>	Output Capacitance	V <sub>CE</sub> = 25V		200		
C <sub>res</sub>	Reverse Transfer Capacitance	f = 1MHz		95		
Q <sub>G</sub>	Gate charge	V <sub>GE</sub> = ±15V, I <sub>C</sub> = 50A V <sub>CE</sub> = 300V		0.5		μC
T <sub>d(on)</sub>	Turn-on Delay Time	Inductive Switching (25°C) V <sub>GE</sub> = ±15V V <sub>Bus</sub> = 300V I <sub>C</sub> = 50A R <sub>G</sub> = 8.2Ω		110		ns
T <sub>r</sub>	Rise Time			45		
T <sub>d(off)</sub>	Turn-off Delay Time			200		
T <sub>f</sub>	Fall Time			40		
T <sub>d(on)</sub>	Turn-on Delay Time	Inductive Switching (150°C) V <sub>GE</sub> = ±15V V <sub>Bus</sub> = 300V I <sub>C</sub> = 50A R <sub>G</sub> = 8.2Ω		120		ns
T <sub>r</sub>	Rise Time			50		
T <sub>d(off)</sub>	Turn-off Delay Time			250		
T <sub>f</sub>	Fall Time			60		
E <sub>off</sub>	Turn-off Switching Energy	V <sub>GE</sub> = ±15V V <sub>Bus</sub> = 300V I <sub>C</sub> = 50A R <sub>G</sub> = 8.2Ω		1.35 1.75		mJ
		T <sub>j</sub> = 25°C T <sub>j</sub> = 150°C				
I <sub>sc</sub>	Short Circuit data	V <sub>GE</sub> ≤ 15V ; V <sub>Bus</sub> = 360V t <sub>p</sub> ≤ 6μs ; T <sub>j</sub> = 150°C		250		A
R <sub>thJC</sub>	Junction to Case Thermal resistance				0.85	°C/W

**1.2 Top diode characteristics (CR1, CR3) (per diode)**

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>		<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
V <sub>RRM</sub>	Maximum Peak Repetitive Reverse Voltage			600			V
I <sub>RM</sub>	Maximum Reverse Leakage Current	V <sub>R</sub> =600V	T <sub>j</sub> = 25°C			25	μA
			T <sub>j</sub> = 125°C			500	
I <sub>F</sub>	DC Forward Current		T <sub>c</sub> = 80°C		25		A
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> = 25A			1.8	2.2	V
		I <sub>F</sub> = 50A			2.2		
		I <sub>F</sub> = 25A	T <sub>j</sub> = 125°C		1.6		
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 25A V <sub>R</sub> = 400V di/dt = 200A/μs	T <sub>j</sub> = 25°C		30		ns
			T <sub>j</sub> = 125°C		175		
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 25A V <sub>R</sub> = 400V di/dt = 200A/μs	T <sub>j</sub> = 25°C		55		nC
			T <sub>j</sub> = 125°C		485		
R <sub>thJC</sub>	Junction to Case Thermal resistance					1.4	°C/W

**2. Bottom switches**
**2.1 Bottom CoolMOS™ characteristics (Per CoolMOS™)**
**Absolute maximum ratings**

<i>Symbol</i>	<i>Parameter</i>	<i>Max ratings</i>	<i>Unit</i>
V <sub>DSS</sub>	Drain - Source Breakdown Voltage	600	V
I <sub>D</sub>	Continuous Drain Current	T <sub>c</sub> = 25°C	49
		T <sub>c</sub> = 80°C	38
I <sub>DM</sub>	Pulsed Drain current	130	
V <sub>GS</sub>	Gate - Source Voltage	±20	V
R <sub>DS(on)</sub>	Drain - Source ON Resistance	45	mΩ
P <sub>D</sub>	Maximum Power Dissipation	T <sub>c</sub> = 25°C	250
I <sub>AR</sub>	Avalanche current (repetitive and non repetitive)	15	A
E <sub>AR</sub>	Repetitive Avalanche Energy	3	mJ
E <sub>AS</sub>	Single Pulse Avalanche Energy	1900	

**Electrical Characteristics**

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>		<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 600V	T <sub>j</sub> = 25°C			250	μA
		V <sub>GS</sub> = 0V, V <sub>DS</sub> = 600V	T <sub>j</sub> = 125°C			500	
R <sub>DS(on)</sub>	Drain – Source on Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 24.5A			40	45	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 3mA		2.1	3	3.9	V
I <sub>GSS</sub>	Gate – Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0V				100	nA

**Dynamic Characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V ; V <sub>DS</sub> = 25V f = 1MHz		7.2		nF
C <sub>oss</sub>	Output Capacitance			8.5		
Q <sub>g</sub>	Total gate Charge	V <sub>GS</sub> = 10V V <sub>Bus</sub> = 300V I <sub>D</sub> = 49A		150		nC
Q <sub>gs</sub>	Gate – Source Charge			34		
Q <sub>gd</sub>	Gate – Drain Charge			51		
T <sub>d(on)</sub>	Turn-on Delay Time	<b>Inductive Switching (125°C)</b> V <sub>GS</sub> = 10V V <sub>Bus</sub> = 400V I <sub>D</sub> = 49A R <sub>G</sub> = 5Ω		21		ns
T <sub>r</sub>	Rise Time			30		
T <sub>d(off)</sub>	Turn-off Delay Time			100		
T <sub>f</sub>	Fall Time			45		
E <sub>on</sub>	Turn-on Switching Energy	<b>Inductive switching @ 25°C</b> V <sub>GS</sub> = 10V ; V <sub>Bus</sub> = 400V I <sub>D</sub> = 49A ; R <sub>G</sub> = 5Ω		675		μJ
E <sub>off</sub>	Turn-off Switching Energy			520		
E <sub>on</sub>	Turn-on Switching Energy	<b>Inductive switching @ 125°C</b> V <sub>GS</sub> = 10V ; V <sub>Bus</sub> = 400V I <sub>D</sub> = 49A ; R <sub>G</sub> = 5Ω		1096		μJ
E <sub>off</sub>	Turn-off Switching Energy			635		
R <sub>thJC</sub>	Junction to Case Thermal resistance				0.5	°C/W

**Source - Drain diode ratings and characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
I <sub>S</sub>	Continuous Source current (Body diode)	T <sub>c</sub> = 25°C		49		A
		T <sub>c</sub> = 80°C		38		
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = - 49A			1.2	V
dv/dt	Peak Diode Recovery ❶				4	V/ns
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> = - 49A V <sub>R</sub> = 350V		600		ns
Q <sub>rr</sub>	Reverse Recovery Charge	di <sub>S</sub> /dt = 100A/μs T <sub>j</sub> = 25°C		17		μC

❶ dv/dt numbers reflect the limitations of the circuit rather than the device itself.

$$I_S \leq -49A \quad di/dt \leq 100A/\mu s \quad V_R \leq V_{DSS} \quad T_j \leq 150^\circ C$$

### 3. Boost chopper Q5, CR5

#### 3.1 Q5 CoolMOS™ characteristics

**Absolute maximum ratings**

Symbol	Parameter	Max ratings	Unit
V <sub>DSS</sub>	Drain - Source Breakdown Voltage	600	V
I <sub>D</sub>	Continuous Drain Current	T <sub>c</sub> = 25°C	49
		T <sub>c</sub> = 80°C	38
I <sub>DM</sub>	Pulsed Drain current	130	
V <sub>GS</sub>	Gate - Source Voltage	±20	V
R <sub>DSon</sub>	Drain - Source ON Resistance	45	mΩ
P <sub>D</sub>	Maximum Power Dissipation	T <sub>c</sub> = 25°C	250
I <sub>AR</sub>	Avalanche current (repetitive and non repetitive)	15	A
E <sub>AR</sub>	Repetitive Avalanche Energy	3	mJ
E <sub>AS</sub>	Single Pulse Avalanche Energy	1900	

**Electrical Characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 600V			250	μA
		T <sub>j</sub> = 25°C				
		V <sub>GS</sub> = 0V, V <sub>DS</sub> = 600V			500	
R <sub>DS(on)</sub>	Drain – Source on Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 24.5A		40	45	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 3mA	2.1	3	3.9	V
I <sub>GSS</sub>	Gate – Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0V			100	nA

**Dynamic Characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V ; V <sub>DS</sub> = 25V f = 1MHz		7.2		nF
C <sub>oss</sub>	Output Capacitance			8.5		
Q <sub>g</sub>	Total gate Charge	V <sub>GS</sub> = 10V V <sub>Bus</sub> = 300V I <sub>D</sub> = 49A		150		nC
Q <sub>gs</sub>	Gate – Source Charge			34		
Q <sub>gd</sub>	Gate – Drain Charge			51		
T <sub>d(on)</sub>	Turn-on Delay Time	<b>Inductive Switching (125°C)</b> V <sub>GS</sub> = 10V V <sub>Bus</sub> = 400V I <sub>D</sub> = 49A R <sub>G</sub> = 5Ω		21		ns
T <sub>r</sub>	Rise Time			30		
T <sub>d(off)</sub>	Turn-off Delay Time			100		
T <sub>f</sub>	Fall Time			45		
E <sub>on</sub>	Turn-on Switching Energy	<b>Inductive switching @ 25°C</b> V <sub>GS</sub> = 10V ; V <sub>Bus</sub> = 400V I <sub>D</sub> = 49A ; R <sub>G</sub> = 5Ω		675		μJ
E <sub>off</sub>	Turn-off Switching Energy			520		
E <sub>on</sub>	Turn-on Switching Energy	<b>Inductive switching @ 125°C</b> V <sub>GS</sub> = 10V ; V <sub>Bus</sub> = 400V I <sub>D</sub> = 49A ; R <sub>G</sub> = 5Ω		1096		μJ
E <sub>off</sub>	Turn-off Switching Energy			635		
R <sub>thJC</sub>	Junction to Case Thermal resistance				0.5	°C/W

**Source - Drain diode ratings and characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
I <sub>S</sub>	Continuous Source current (Body diode)	T <sub>c</sub> = 25°C		49		A
		T <sub>c</sub> = 80°C		38		
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = - 49A			1.2	V
dv/dt	Peak Diode Recovery ❶				4	V/ns
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> = - 49A V <sub>R</sub> = 350V di <sub>S</sub> /dt = 100A/μs		600		ns
Q <sub>rr</sub>	Reverse Recovery Charge		T <sub>j</sub> = 25°C		17	

❶ dv/dt numbers reflect the limitations of the circuit rather than the device itself.

$$I_S \leq -49A \quad di/dt \leq 100A/\mu s \quad V_R \leq V_{DSS} \quad T_j \leq 150^\circ C$$

### 3.2 Chopper diode characteristics (CR5)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V <sub>RRM</sub>	Maximum Peak Repetitive Reverse Voltage			600			V
I <sub>RM</sub>	Maximum Reverse Leakage Current	V <sub>R</sub> =600V	T <sub>j</sub> = 25°C			25	μA
			T <sub>j</sub> = 125°C			500	
I <sub>F</sub>	DC Forward Current	T <sub>c</sub> = 80°C			60		A
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> = 60A			1.7	2.3	V
		I <sub>F</sub> = 120A			2		
		I <sub>F</sub> = 60A	T <sub>j</sub> = 125°C		1.4		
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 60A V <sub>R</sub> = 400V di/dt = 200A/μs	T <sub>j</sub> = 25°C		70		ns
			T <sub>j</sub> = 125°C		140		
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 60A V <sub>R</sub> = 400V di/dt = 200A/μs	T <sub>j</sub> = 25°C		100		nC
			T <sub>j</sub> = 125°C		690		
R <sub>thJC</sub>	Junction to Case Thermal resistance					0.85	°C/W

### 4. By pass diode (CR6)

#### Absolute maximum ratings

Symbol	Parameter		Max ratings	Unit
V <sub>R</sub>	Maximum DC reverse Voltage		1600	V
V <sub>RRM</sub>	Maximum Peak Repetitive Reverse Voltage			
I <sub>F</sub>	DC Forward Current	T <sub>C</sub> = 80°C	40	A
I <sub>FSM</sub>	Non-Repetitive Forward Surge Current	t=10ms T <sub>J</sub> = 45°C	400	

#### Electrical Characteristics

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
I <sub>R</sub>	Reverse Current	V <sub>R</sub> = 1600V	T <sub>j</sub> = 25°C		20		μA
			T <sub>j</sub> = 125°C		2		mA
V <sub>F</sub>	Forward Voltage	I <sub>F</sub> = 40A	T <sub>j</sub> = 25°C		1.3		V
			T <sub>j</sub> = 125°C		1.1		
V <sub>T</sub>	On – state Voltage				0.8		V
r <sub>T</sub>	On – state Slope resistance				10.5		mΩ
R <sub>thJC</sub>	Junction to Case Thermal resistance					1.5	°C/W

### 5. Temperature sensor

#### Temperature sensor NTC (see application note APT0406 on www.microsemi.com for more information).

Symbol	Characteristic	Min	Typ	Max	Unit
R <sub>25</sub>	Resistance @ 25°C		50		kΩ
ΔR <sub>25</sub> /R <sub>25</sub>			5		%
B <sub>25/85</sub>	T <sub>25</sub> = 298.15 K		3952		K
ΔB/B		T <sub>C</sub> =100°C	4		%

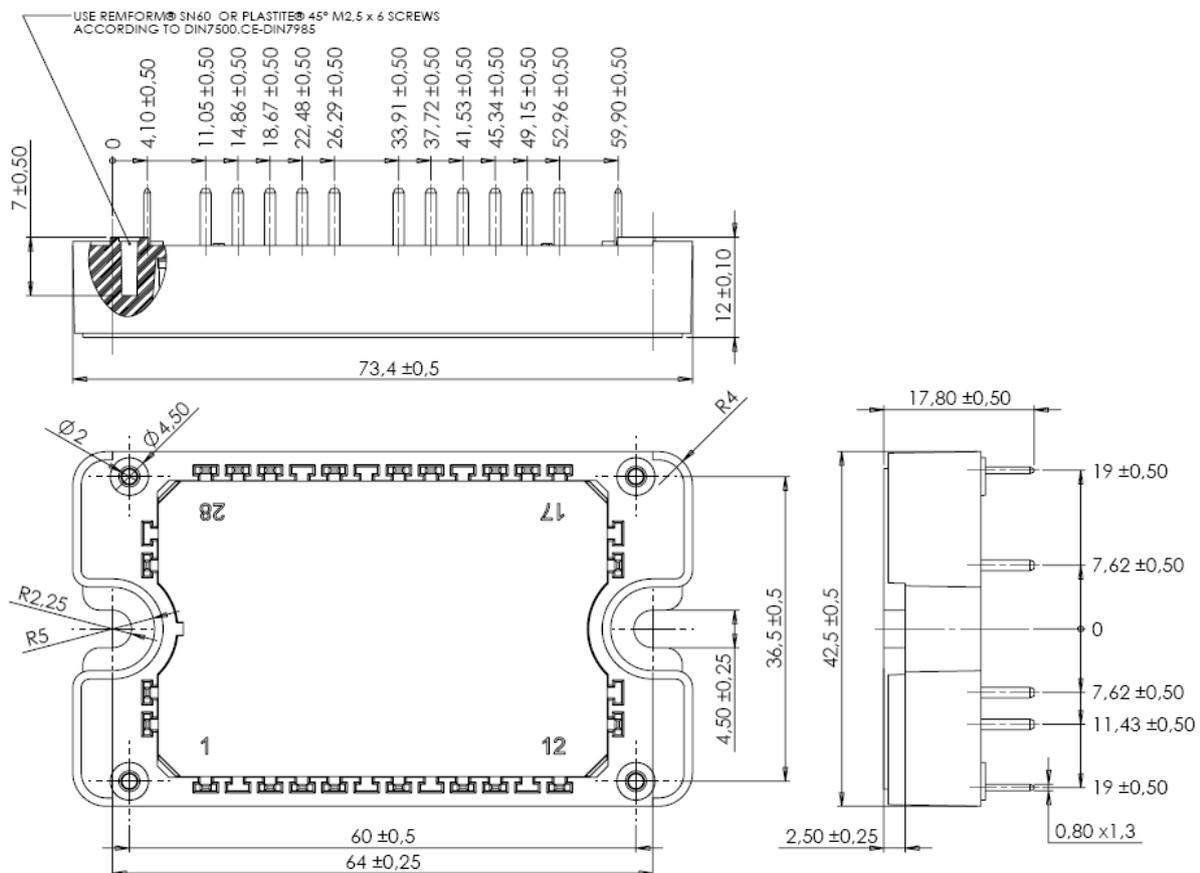
$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$

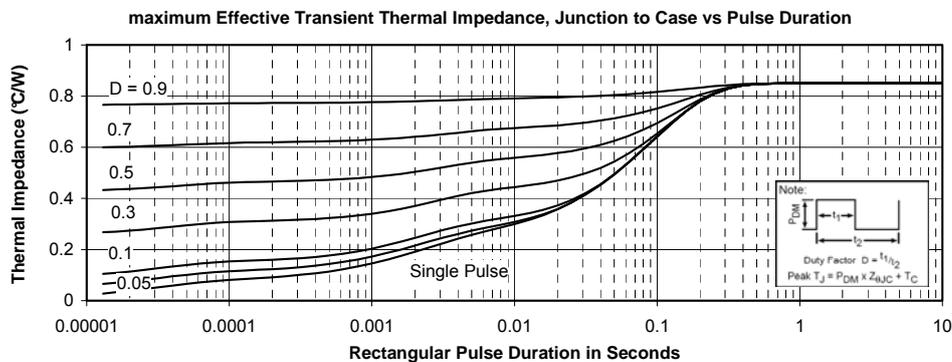
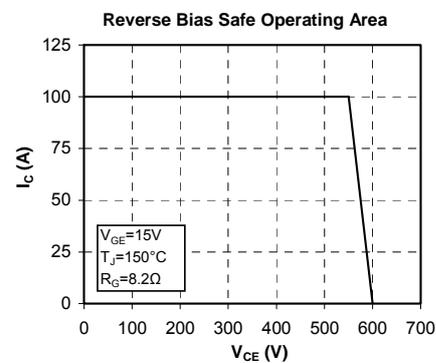
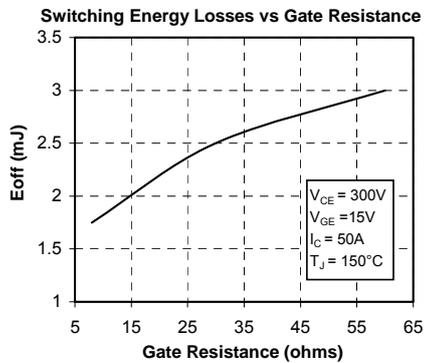
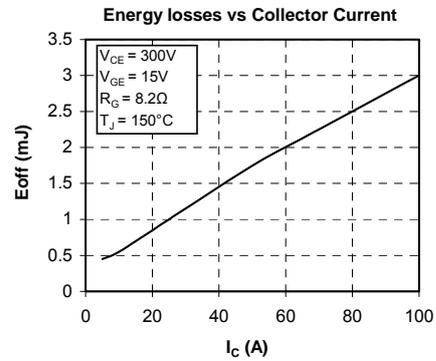
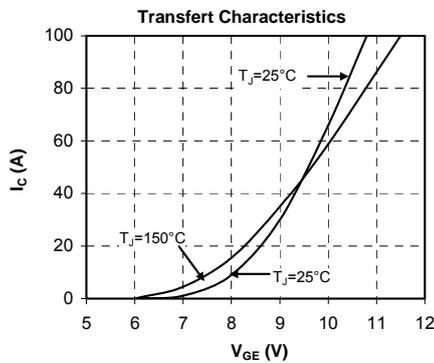
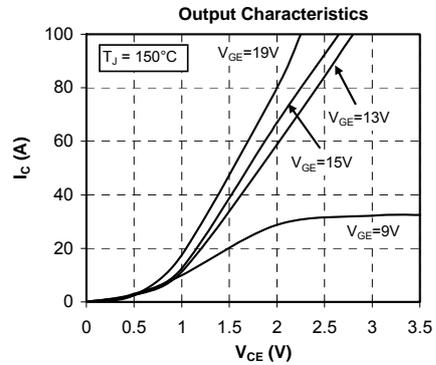
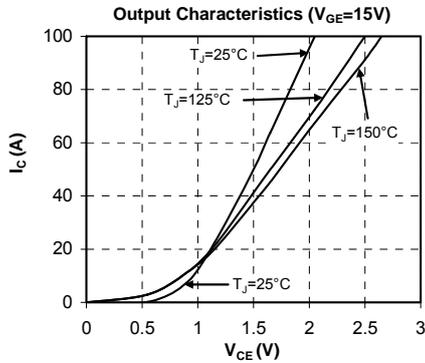
T: Thermistor temperature  
 R<sub>T</sub>: Thermistor value at T

**6. Package characteristics**

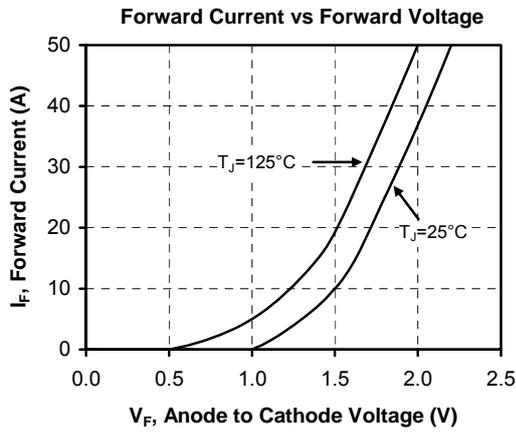
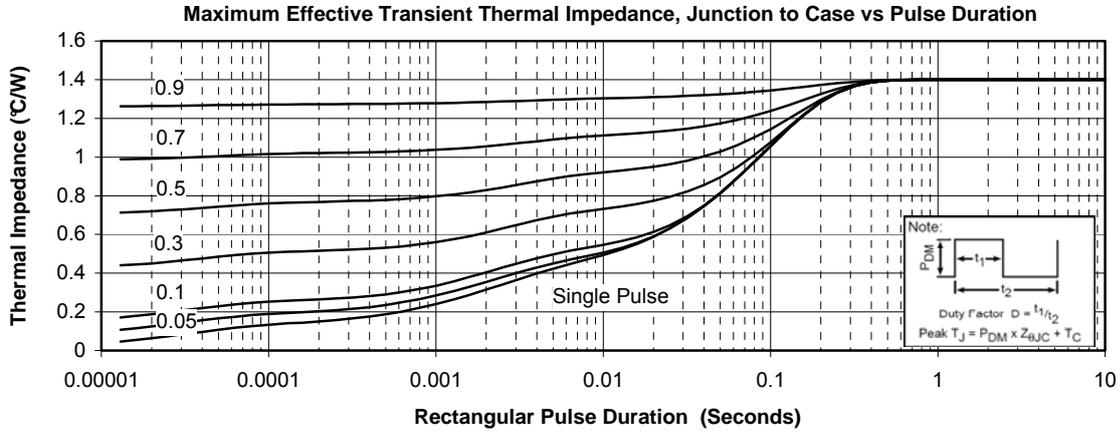
Symbol	Characteristic	Min	Typ	Max	Unit	
V <sub>ISOL</sub>	RMS Isolation Voltage, any terminal to case t=1 min, I <sub>isol</sub> <1mA, 50/60Hz	4000			V	
T <sub>J</sub>	Operating junction temperature range	-40		150*	°C	
T <sub>STG</sub>	Storage Temperature Range	-40		125		
T <sub>C</sub>	Operating Case Temperature	-40		100		
Torque	Mounting torque	To heatsink	M4	2.5	4.7	N.m
Wt	Package Weight				110	g

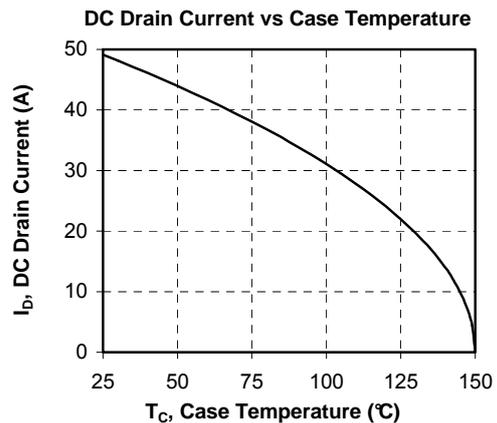
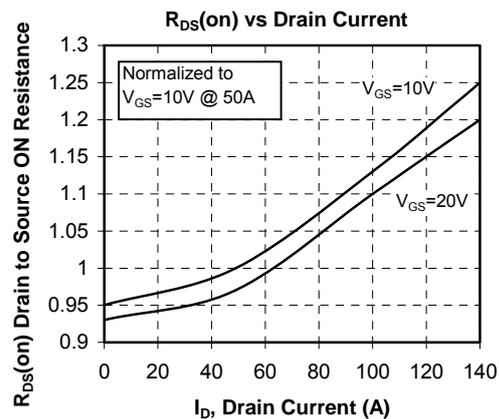
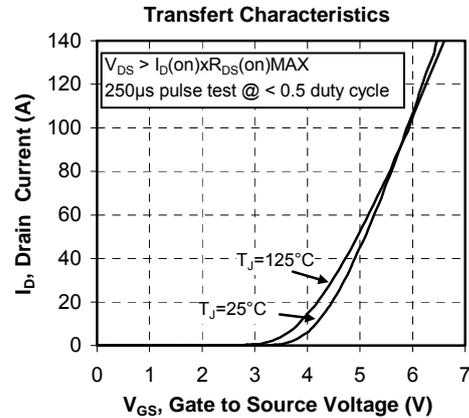
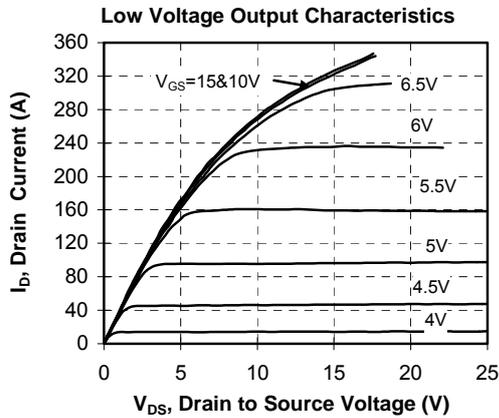
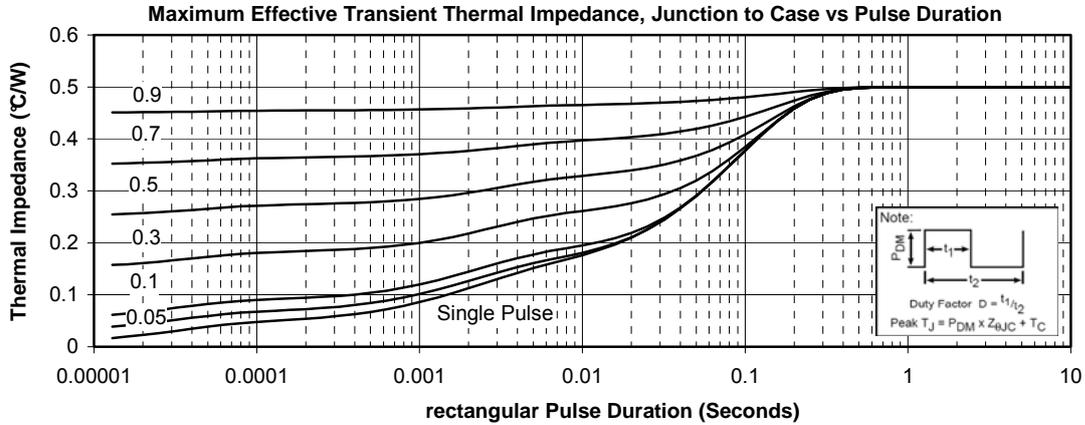
\* T<sub>j</sub>=175°C for Trench & Field Stop IGBT3

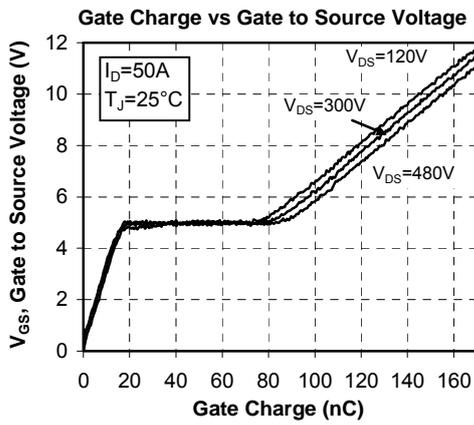
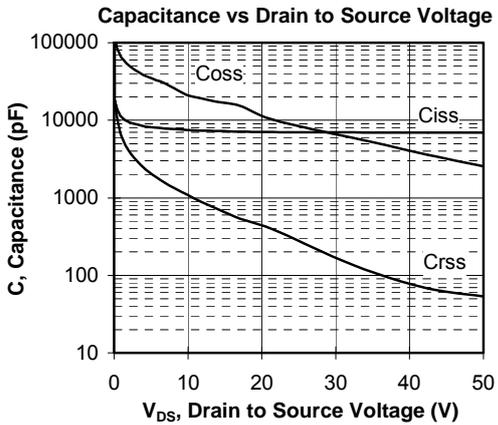
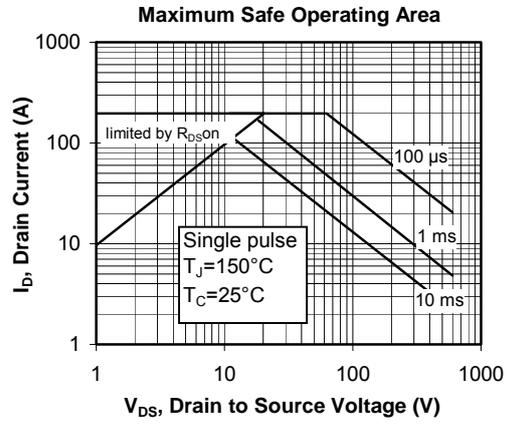
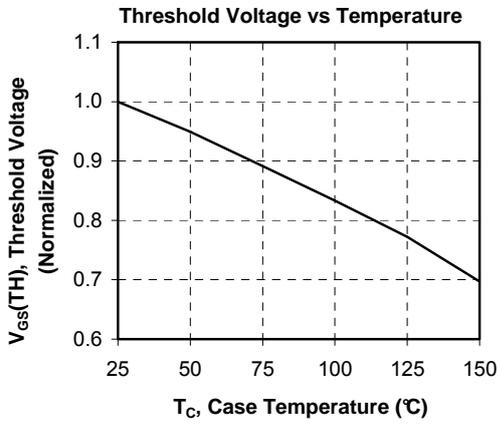
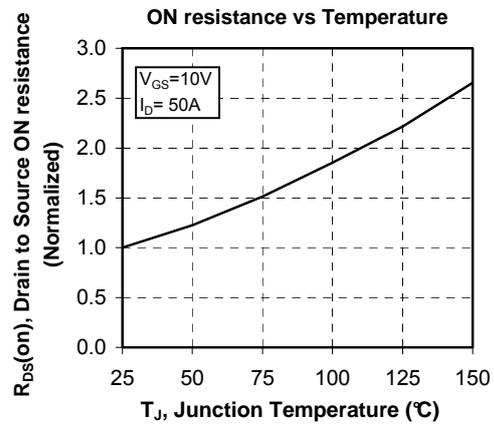
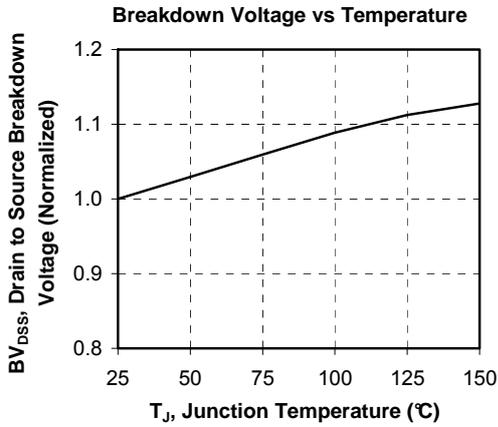
**7. SP3 Package outline (dimensions in mm)**


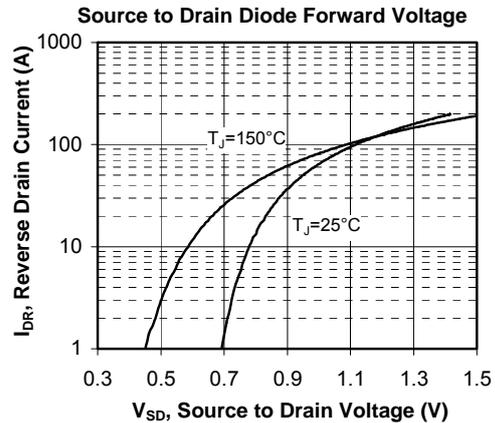
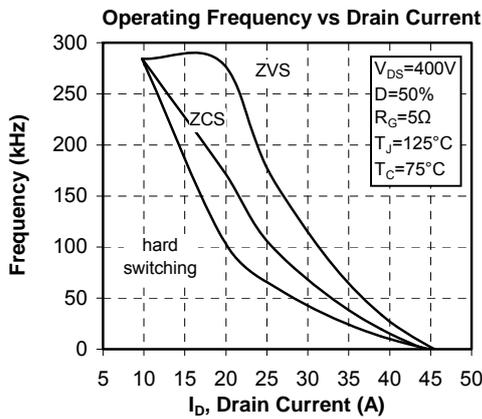
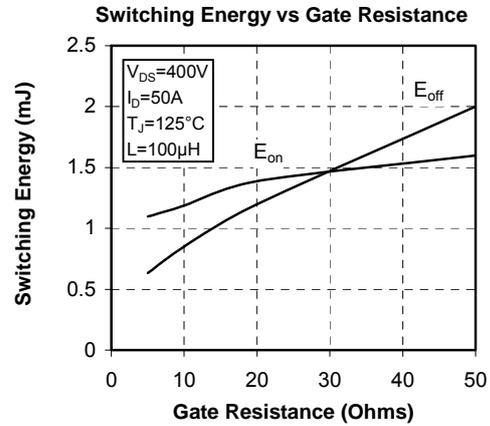
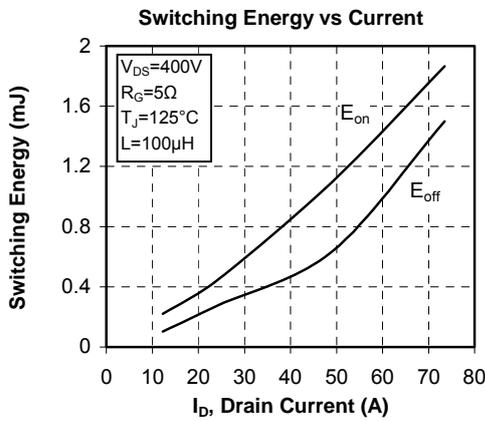
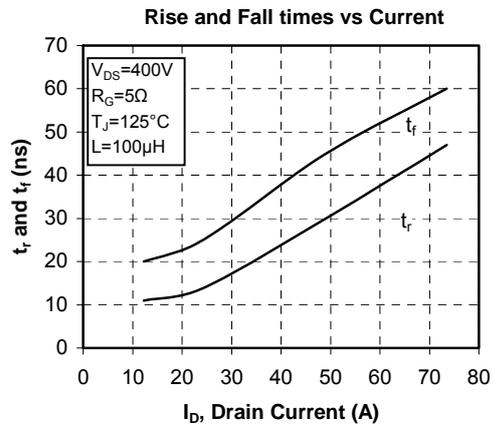
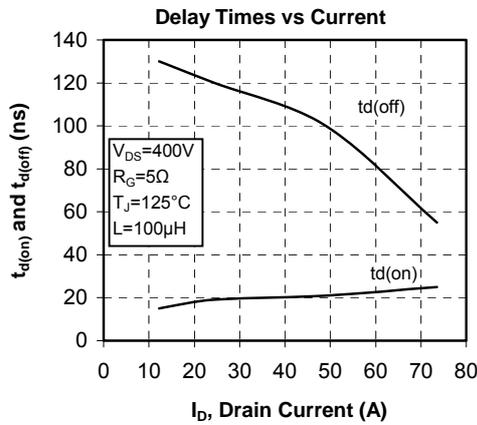
**8. Top switches curves**
**8.1 Top Trench + Field Stop IGBT3 typical performance curves (per IGBT)**


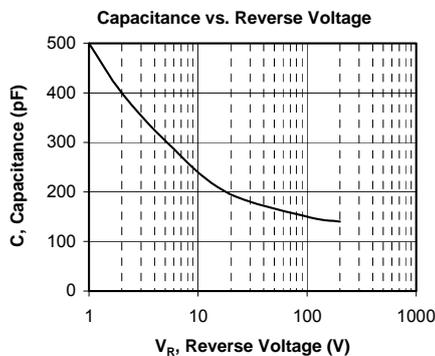
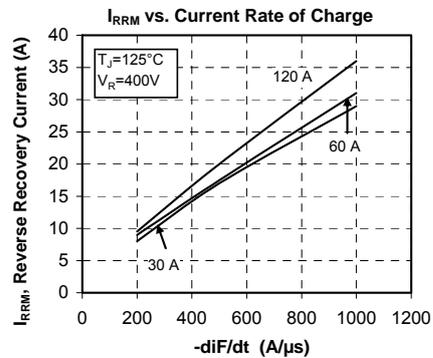
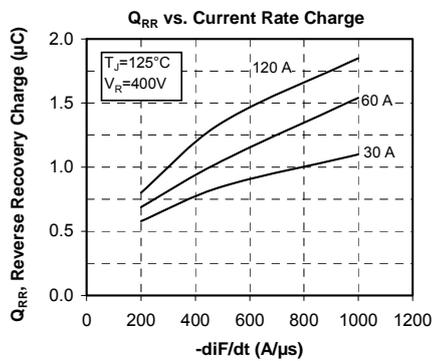
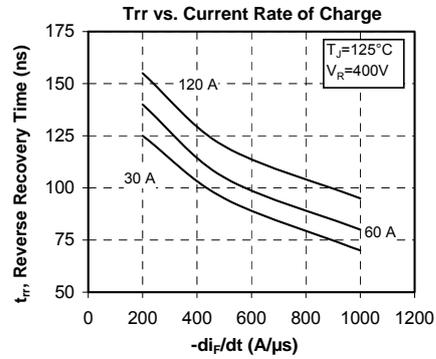
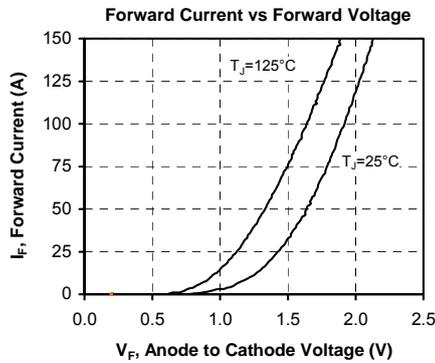
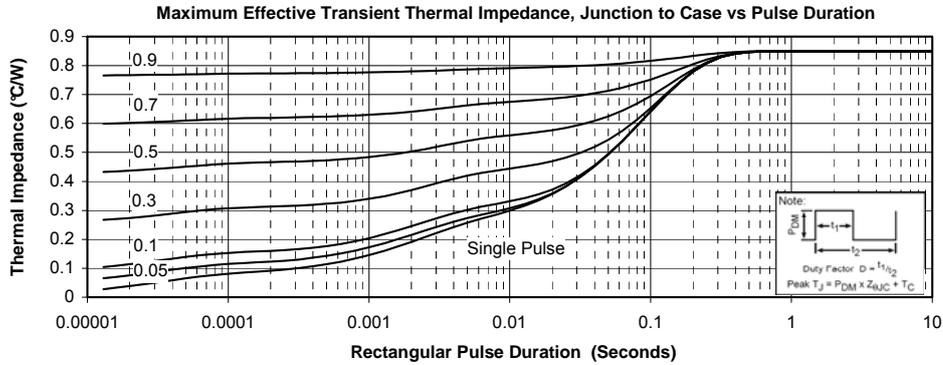
### 8.2 Top diode characteristics (CR1, CR3) (per diode)

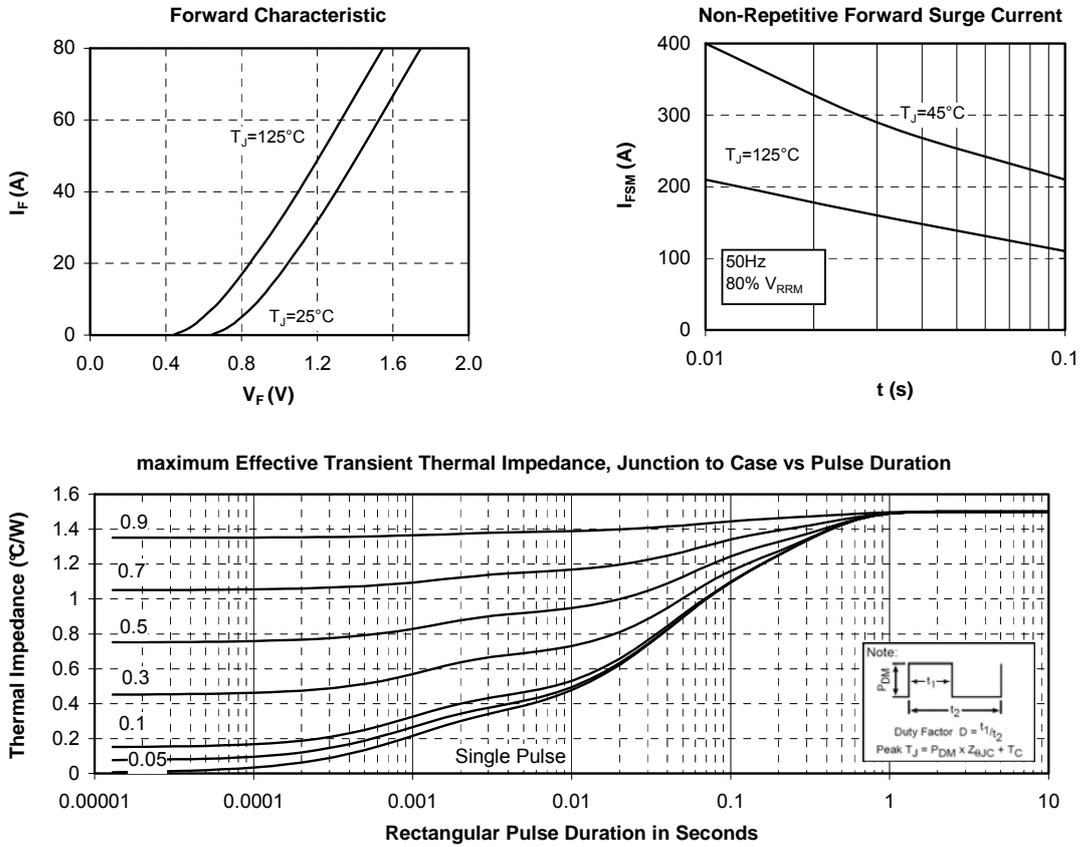


**9. Bottom switches and CoolMOS™ chopper curves (per CoolMOS™)**






**10. Chopper diode curves**


**11. Typical by pass CR6 diode curves**


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